



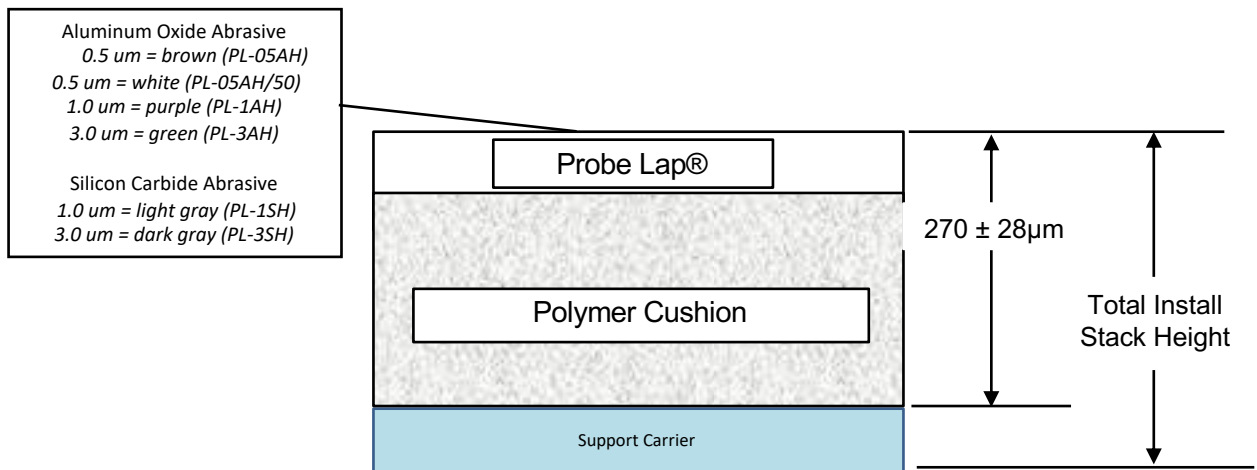
GENERAL

Probe Refresh® is precision lapping film with a cushioned under layer. The lapping film is built using aluminum-oxide or silicon-carbide abrasive grit. The cushion under layer is a high quality compliant polymer. Probe Refresh® can be mounted on various substrates and abrasion plates used for on-line and off-line probe cleaning. Probe Refresh® is used as a direct replacement for on-line lapping film applications. Probe Refresh® has an operating temperature range -50C to 125C. With additional processing, tempered Probe Refresh® high temperature capable cleaning wafers and cleaning sheets can be used at test temperatures up to -50C to 150C.

Frequent use of Probe Refresh®, will reduce the cleaning frequency and number of touchdowns required to remove bonded or embedded debris. Cleaning frequency and cleaning touchdowns will vary according to the specific testing environment.

Advanced and fine pitch probe card technologies cannot withstand high frictional loading or deformation against abrasive films, such as the top layer of Probe Refresh®. For these advanced probe technologies, International Test Solutions recommends a non-destructive, low impact cleaning technique such as Probe Polish® to collect debris, clean the contact surface, and maintain the tip shape.

CROSS SECTION



	Cleaning Material Configuration			
	Sheet	200mm Wafer	300mm Wafer	Custom Install
Polymer Layer Thickness	270 µm (nominal)	270 µm (nominal)	270 µm (nominal)	270 µm (nominal)
Support Carrier	150 µm (PET nominal)	725 ± 20µm (SEMI Standard)	775 ± 20µm (SEMI Standard)	Contact ITS
Total Installed Stack Height	420 ± 30µm	995 ± 50µm	1045 ± 50 µm	Contact ITS

PROBE REFRESH®

PCC PD-PR001

For more information, please contact:

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